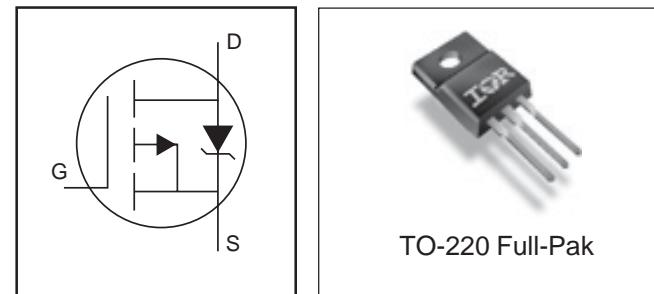


IRLIB9343PbF

Features

- Advanced Process Technology
- Key Parameters Optimized for Class-D Audio Amplifier Applications
- Low $R_{DS(ON)}$ for Improved Efficiency
- Low Q_g and Q_{sw} for Better THD and Improved Efficiency
- Low Q_{rr} for Better THD and Lower EMI
- 175°C Operating Junction Temperature for Ruggedness
- Repetitive Avalanche Capability for Robustness and Reliability
- Lead-Free

Key Parameters		
V_{DS}	-55	V
$R_{DS(ON)}$ typ. @ $V_{GS} = -10V$	93	$m\Omega$
$R_{DS(ON)}$ typ. @ $V_{GS} = -4.5V$	150	$m\Omega$
Q_g typ.	31	nC
T_J max	175	°C



Description

This Digital Audio HEXFET® is specifically designed for Class-D audio amplifier applications. This MosFET utilizes the latest processing techniques to achieve low on-resistance per silicon area. Furthermore, Gate charge, body-diode reverse recovery and internal Gate resistance are optimized to improve key Class-D audio amplifier performance factors such as efficiency, THD and EMI. Additional features of this MosFET are 175°C operating junction temperature and repetitive avalanche capability. These features combine to make this MosFET a highly efficient, robust and reliable device for Class-D audio amplifier applications.

Absolute Maximum Ratings

	Parameter	Max.	Units
V_{DS}	Drain-to-Source Voltage	-55	V
V_{GS}	Gate-to-Source Voltage	± 20	
I_D @ $T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ -10V$	-14	A
I_D @ $T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ -10V$	-10	
I_{DM}	Pulsed Drain Current ①	-60	
$P_D @ T_C = 25^\circ C$	Power Dissipation	33	W
$P_D @ T_C = 100^\circ C$	Power Dissipation	20	
	Linear Derating Factor	0.26	W/°C
T_J	Operating Junction and Storage Temperature Range	-40 to + 175	°C
T_{STG}			
	Mounting Torque, 6-32 or M3 screw	10 (1.1)	lbf•in (N•m)

Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ④	—	3.84	°C/W
$R_{\theta JA}$	Junction-to-Ambient ④	—	65	

Notes ① through ⑤ are on page 7

Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

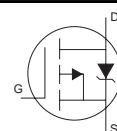
	Parameter	Min.	Typ.	Max.	Units	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	-55	—	—	V	$V_{\text{GS}} = 0\text{V}, I_D = -250\mu\text{A}$
$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	-52	—	mV/ $^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = -1\text{mA}$
$R_{\text{DS(on)}}$	Static Drain-to-Source On-Resistance	—	93	105	$\text{m}\Omega$	$V_{\text{GS}} = -10\text{V}, I_D = -3.4\text{A}$ ③
		—	150	170		$V_{\text{GS}} = -4.5\text{V}, I_D = -2.7\text{A}$ ③
$V_{\text{GS(th)}}$	Gate Threshold Voltage	-1.0	—	—	V	$V_{\text{DS}} = V_{\text{GS}}, I_D = -250\mu\text{A}$
$\Delta V_{\text{GS(th)}}/\Delta T_J$	Gate Threshold Voltage Coefficient	—	-3.7	—	mV/ $^\circ\text{C}$	
I_{DSS}	Drain-to-Source Leakage Current	—	—	-2.0	μA	$V_{\text{DS}} = -55\text{V}, V_{\text{GS}} = 0\text{V}$
		—	—	-25		$V_{\text{DS}} = -55\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	-100	nA	$V_{\text{GS}} = -20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	100		$V_{\text{GS}} = 20\text{V}$
g_{fs}	Forward Transconductance	5.3	—	—	S	$V_{\text{DS}} = -25\text{V}, I_D = -14\text{A}$
Q_g	Total Gate Charge	—	31	47		$V_{\text{DS}} = -44\text{V}$
Q_{gs}	Pre-V _{th} Gate-to-Source Charge	—	7.1	—		$V_{\text{GS}} = -10\text{V}$
Q_{gd}	Gate-to-Drain Charge	—	8.5	—		$I_D = -14\text{A}$
Q_{godr}	Gate Charge Overdrive	—	15	—		See Fig. 6 and 19
$t_{\text{d(on)}}$	Turn-On Delay Time	—	9.5	—	ns	$V_{\text{DD}} = -28\text{V}, V_{\text{GS}} = -10\text{V}$ ③
t_r	Rise Time	—	24	—		$I_D = -14\text{A}$
$t_{\text{d(off)}}$	Turn-Off Delay Time	—	21	—		$R_G = 2.5\Omega$
t_f	Fall Time	—	9.5	—		
C_{iss}	Input Capacitance	—	660	—	pF	$V_{\text{GS}} = 0\text{V}$
C_{oss}	Output Capacitance	—	160	—		$V_{\text{DS}} = -50\text{V}$
C_{rss}	Reverse Transfer Capacitance	—	72	—		$f = 1.0\text{MHz}$, See Fig.5
C_{oss}	Effective Output Capacitance	—	280	—		$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 0\text{V to } -44\text{V}$
L_D	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6mm (0.25in.)
L_S	Internal Source Inductance	—	7.5	—		from package and center of die contact

Avalanche Characteristics

	Parameter	Typ.	Max.	Units
E_{AS}	Single Pulse Avalanche Energy ②	—	190	mJ
I_{AR}	Avalanche Current ⑤	See Fig. 14, 15, 17a, 17b	A	
E_{AR}	Repetitive Avalanche Energy ⑤			

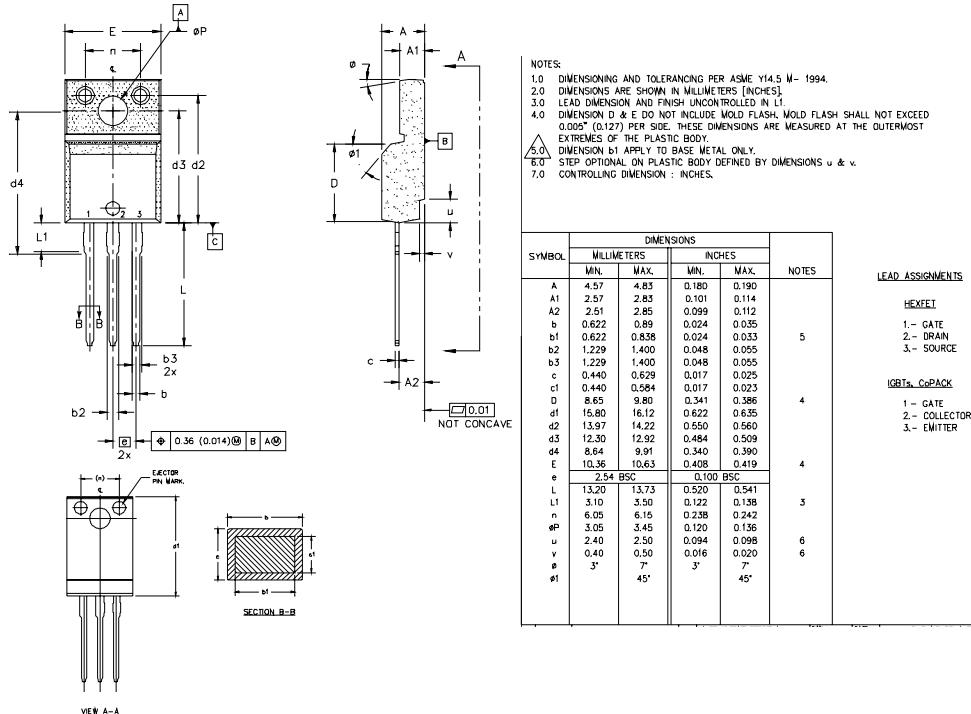
Diode Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S @ T_C = 25^\circ\text{C}$	Continuous Source Current (Body Diode)	—	—	-14	A	MOSFET symbol showing the integral reverse p-n junction diode.
	Pulsed Source Current (Body Diode) ①	—	—	-60		
V_{SD}	Diode Forward Voltage	—	—	-1.2	V	$T_J = 25^\circ\text{C}, I_S = -14\text{A}, V_{\text{GS}} = 0\text{V}$ ③
t_{rr}	Reverse Recovery Time	—	57	86	ns	$T_J = 25^\circ\text{C}, I_F = -14\text{A}$
Q_{rr}	Reverse Recovery Charge	—	120	180	nC	$dI/dt = 100\text{A}/\mu\text{s}$ ③



TO-220 Full-Pak Package Outline

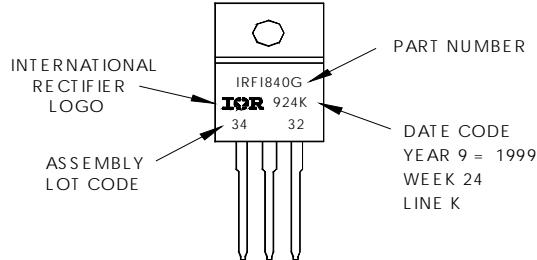
Dimensions are shown in millimeters (inches)



TO-220 Full-Pak Part Marking Information

EXAMPLE: THIS IS AN IRFI840G
WITH ASSEMBLY
LOT CODE 3432
ASSEMBLED ON WW 24 1999
IN THE ASSEMBLY LINE "K"

Note: "P" in assembly line
position indicates "Lead-Free"



TO-220 FullPak packages are not recommended for Surface Mount Application.

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting $T_J = 25^\circ\text{C}$, $L = 3.89\text{mH}$, $R_G = 25\Omega$, $I_{AS} = -10\text{A}$.
- ③ Pulse width $\leq 400\mu\text{s}$; duty cycle $\leq 2\%$.
- ④ R_θ is measured at T_J of approximately 90°C .
- ⑤ Limited by T_{jmax} . See Figs. 14, 15, 17a, 17b for repetitive avalanche information

Data and specifications subject to change without notice.
This product has been designed for the Industrial market.

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